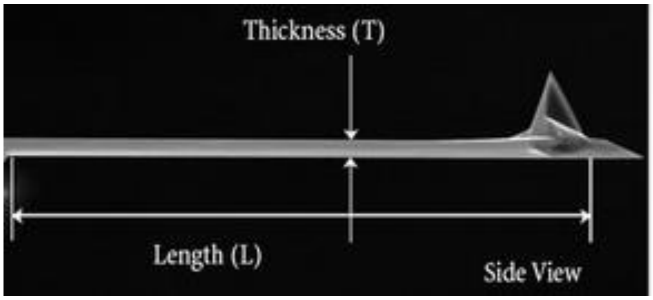
K-TEK
NANOTECHNOLOGY

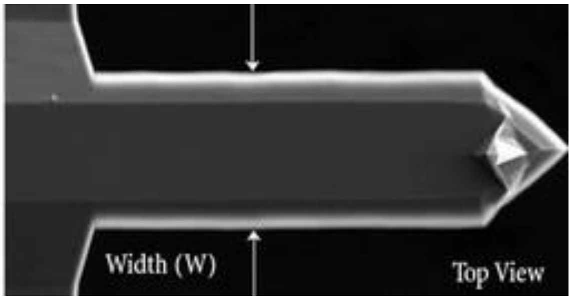
GOLDEN SERIES PROBES

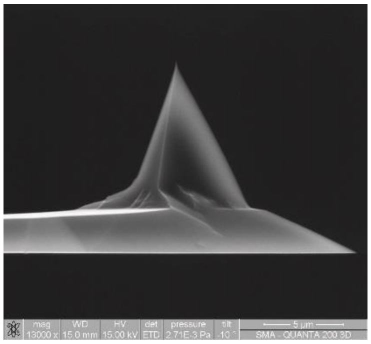
The everyday use standard Golden Series AFM silicon probes featuring an extremely sharp tip for high quality imaging! Various probe options available to meet your specific application. The standard chip sizes make these probes compatible with most AFM systems.

SPECIFICATIONS

SKU	Cantilever length, l±10, µm	Cantilever width, w±5, µm	Thickness, ±0.5, µm	Resonant frequency, kHz			Force constant, N/m		
				Min	Typical	Max	Min	Typical	Max
CSG01	450	47.5	1.25	4	9.8	17	0.003	0.03	0.13
CSG10	225	47.5	1.25	8	22	39	0.01	0.11	0.5
CSG30	225	25	2	26	48	76	0.13	0.6	2
NSG01	150	27	2.8	87	150	230	1.45	5.1	15.1
NSG03	150	24	1.75	47	90	150	0.35	1.74	6.1
NSG10	125	27	2.75	140	240	390	3.1	11.8	37.6
NSG30	125	30	4	240	320	440	22	40	100
FMG01	225	28	3	40	60	96	1	3	5
MFM01	225	28	3	47	70	90	1	3	5
MFM_LM	225	28	3	47	70	90	1	3	5







Material	Single Crystal Silicon, N-type, 0.01-0.025 Ohm-cm, Antimony doped
Chip size	1.6x3.4x0.3mm
Cantilever geometry	Rectangular (cross-section is trapezium)
Number of cantilevers	1
Back side coating	Au reflective
Tip geometry	Tetrahedral, the last 500nm from tip apex is cylindrical
Tip height	14-15 µm
Tip aspect ratio	3:1-7:1
Tip curvature radius (Nom)	6nm (uncoated)
Tip curvature radius (Max)	10nm (guaranteed)

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